Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/523,030	MIYA ET AL	
Examiner	**Art Unit**	
Tran N. Nguyen	2834	

SEARCHED			
Class	Subclass	Date	Examiner
310	90.5	8/16/07	TNN
	156.68		
	156.12		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR